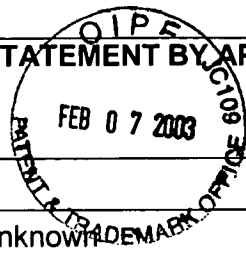


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5730/TCG/ WCVD/LE	Serial No. 10/023,125
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Yoo, et al.	Confirmation No.: 5485
(Use several sheets if necessary)		Filing Date Dec. 17, 2001	Group Unknown
Examiner Unknown			

**U.S. Patent Documents**

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
/F.S./	A1	6,482,740	11/19/02	Soininen, et al.	438	686	05/15/01
/F.S./	A2	6,482,733	11/19/02	Raaijmakers, et al.	438	633	04/26/01
/F.S./	A3	6,475,910	11/05/02	Sneh	438	685	09/22/00
/F.S./	A4	6,475,276	11/05/02	Elers, et al.	117	84	10/13/00
/F.S./	A5	6,451,695	09/17/02	Sneh	438	685	12/22/00
/F.S./	A6	6,451,119	09/17/02	Sneh, et al.	118	715	11/29/00
/F.S./	A7	6,447,933	09/10/02	Wang, et al.	428	635	04/30/01
/F.S./	A8	6,423,619	07/23/02	Grant, et al.	438	589	11/30/01
/F.S./	A9	6,420,189	07/16/02	Lopatin	438	2	04/27/01
/F.S./	A10	6,391,785	05/21/02	Satta, et al.	438	704	08/23/00
/F.S./	A11	6,369,430	04/09/02	Adetutu, et al.	257	382	04/02/01
/F.S./	A12	6,368,954	04/09/02	Lopatin, et al.	438	627	07/28/00
/F.S./	A13	6,358,829	03/19/02	Yoon, et al.	438	597	09/16/99

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
/F.S./	B1	1 033 5264	12/18/98	JP (Abst)	H01L	21/285	<input type="checkbox"/>	<input type="checkbox"/>
/F.S./	B2	0 406 4223	02/28/92	JP (Abst)	H01L	21/285	<input type="checkbox"/>	<input type="checkbox"/>
/F.S./	B3	6 203 3768	02/13/87	JP (Abst)	C23C	16/14	<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
/F.S./	C1	Lee, et al., "Pulsed Nucleation for Ultra-High Aspect Ratio Tungsten Plugfill," Conference Proceedings ULSI XV111 (2002) Materials Research Society
/F.S./	C2	Sone, et al., "Formation of Low Pressure Chemically Vapour Deposited W Thin Film on Silicon Dioxide for Gate Electrode Application," Thin Solid Films 253 (1994) 377-381
/F.S./	C3	International Search Report, dated November 25, 2002 for PCT/US02/22486

Examiner /Francis Smith/	Date Considered 12/18/2007
--------------------------	----------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5730/TCG/ WCVD/LE	Serial No. 10/023,125
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Yoo, et al.	Confirmation No.: 5485
(Use several sheets if necessary)		Filing Date Dec. 17, 2001	Group Unknown
Examiner	Unknown		

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
/F.S./	A15	6,355,561	03/12/02	Sandhu, et al.	438	676	11/21/00
/F.S./	A16	6,333,260	12/25/01	Kwon, et al.	438	643	06/24/99
/F.S./	A17	6,305,314	10/23/01	Sneh, et al.	118	723 R	12/17/99
/F.S./	A18	6,287,965	09/11/01	Kang, et al.	438	648	02/23/00
/F.S./	A19	6,284,646	09/04/01	Leem	438	629	08/19/98
/F.S./	A20	6,200,893	03/13/01	Sneh	438	685	03/11/89
/F.S./	A21	6,113,699	09/05/00	Hansen	118	715	11/26/97
/F.S./	A22	6,042,652	03/28/00	Hyun, et al.	118	719	09/07/99
/F.S./	A23	5,994,775	11/30/99	Zhao, et al.	257	751	09/17/97
/F.S./	A24	5,306,666	04/26/94	Izumi	437	192	07/21/93
/F.S./	A25	2002/0162506	11/07/02	Sneh, et al.	118	715	06/28/02
/F.S./	A26	2002/0155722	10/24/02	Satta, et al.	438	704	04/15/02
/F.S./	A27	2002/0121697	09/05/02	Marsh	257	751	04/30/02

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B4						<input type="checkbox"/>	<input type="checkbox"/>
	B5						<input type="checkbox"/>	<input type="checkbox"/>
	B6						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C4	
	C5	
	C6	

Examiner /Francis Smith/

Date Considered 12/18/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5730/TCG/ WCVD/LE	Serial No. 10/023,125
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Yoo, et al.	Confirmation No.: 5485
(Use several sheets if necessary)		Filing Date Dec. 17, 2001	Group Unknown
Examiner	Unknown		

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
/F.S./	A28	2002/0117399	08/29/02	Chen, et al.	205	125	02/23/01
/F.S./	A29	2002/0109168	08/15/02	Kim, et al.	257	295	01/30/02
/F.S./	A30	2002/0106846	08/08/02	Seutter, et al.	438	200	02/02/01
/F.S./	A31	2002/0105088	08/08/02	Yang, et al.	257	774	10/31/01
/F.S./	A32	2002/0090829	07/11/02	Sandhu, et al.	438	761	01/31/02
/F.S./	A33	2002/0086507	07/04/02	Park, et al.	438	585	12/26/01
/F.S./	A34	2002/0076507	06/20/02	Chiang, et al.	427	569	10/24/01
/F.S./	A35	2002/0061612	05/23/02	Sandhu, et al.	438	151	01/14/02
/F.S./	A36	2002/0055235	05/09/02	Agarwal, et al.	438	430	10/29/01
/F.S./	A37	2002/0048880	04/25/02	Lee	438	253	08/08/01
/F.S./	A38	2002/0031618	03/14/02	Sherman	427	569	10/09/01
/F.S./	A39	2002/0037630	03/28/02	Agarwal, et al.	438	430	10/29/01
/F.S./	A40	2002/0019121	02/14/02	Pyo	438	618	06/20/01

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B7						<input type="checkbox"/>	<input type="checkbox"/>
	B8						<input type="checkbox"/>	<input type="checkbox"/>
	B9						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C7	
	C8	
	C9	

Examiner /Francis Smith/

Date Considered 12/18/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5730/TCG/ WCVD/LE	Serial No. 10/023,125
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Yoo, et al.	Confirmation No.: 5485
(Use several sheets if necessary)		Filing Date Dec. 17, 2001	Group Unknown
Examiner	Unknown		

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
/F.S./	A41	2002/0004293	01/10/02	Soininen, et al.	438	584	05/15/01
/F.S./	A42	2001/0054769	12/27/01	Raaijmakers, et al.	257	758	04/26/01
/F.S./	A43	2001/0029094	10/11/01	Mee-Young, et al.	438	597	09/16/99
/F.S./	A44	2001/0024387	09/27/01	Raaijmakers, et al.	365	200	02/22/01
/F.S./	A45	2001/0002280	05/31/01	Sneh	427	255.28	12/22/00
/F.S./	A46	2001/0009695	07/26/01	Saanila, et al.	427	255.39	01/18/01

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B10						<input type="checkbox"/>	<input type="checkbox"/>
	B11						<input type="checkbox"/>	<input type="checkbox"/>
	B12						<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
	C10	
	C11	
	C12	

Examiner /Francis Smith/

Date Considered 12/18/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.